

INFORMATION DISCLOSURE CITATION

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ATTY DOCKET NO.

02008.073001; AD-0069PCTUS

SERIAL NO.

10/031,823

Kouichi WADA et al.

FILING

January 18, 2002

GROUP

2829

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
MW	A1	5,613,861	03/25/1997	Smith et al.	439	81	06/07/1995

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

MW	A2	Donald L. Smith et al., "Flip-Chip Bonding on 6-um Pitch using Thin-Film Microspring Technology," Proceedings of the 48th Electronic Components and Technology Conference; Seattle, Washington; May 1998; copyright 1998 IEEE; 3 pages
MW	A3	Soonil Hong et al., "DESIGN AND FABRICATION OF A MONOLITHIC HIGH-DENSITY PROBE CARD FOR HIGH-FREQUENCY ON-WATER TESTING," IEDM 89, pp. 289-292 (4 pages) (no month)

EXAMINER

[Signature]

DATE CONSIDERED

12/18/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE STATEMENT
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Docket Number (Optional)

02008/073001

Application Number

10/031823

Applicant(s)
Kouichi WADA et al.

PCT/PT 18 JAN 2002

Filing Date

Group Art Unit

2829

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
mb	A1	2000-317900A	11/21/2000	Japan	—	—		
	A2	9-126833A	05/16/1997	Japan	—	—		
	A3	2000-65852A	03/03/2000	Japan	—	—		
	A4	1-128381A	05/22/1989	Japan	—	—		
mb	A5	11-160355A	06/18/1999	Japan	—	—		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

mb	A6	Seichi HATA, et al.; "Hakamaky Kinzoku Glass wo mochiita Bisai Kouzoubutsu no Seisaku (Dai 1 Hou)"; Seimitsu Kougakkaishi, January 2000, Vol. 66, No. 1, pp. 96-101

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